

Notice of References Cited	Application/Control No. 10/665,204	Applicant(s)/Patent Under Reexamination WANG ET AL.	
	Examiner A. Sefer	Art Unit 2826	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0149827	10-2002	Fujimura et al.	359/228
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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FOREIGN PATENT DOCUMENTS

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